

Search Notes

Application/Control No.

10/823,558

Examiner

Hae M. Hyeon

Applicant(s)/Patent under
Reexamination

WADE ET AL.

Art Unit

2839

SEARCHED

Class	Subclass	Date	Examiner
439	15	3/05	hmb
439	164	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR